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## PATENT ABSTRACTS OF JAPAN

(11)Publication number:

05-260385

(43) Date of publication of application: 08.10.1993

(51)Int.CI.

HO4N 5/335

(21)Application number : 04-058366

(71)Applicant : SONY CORP

(22)Date of filing:

16.03.1992

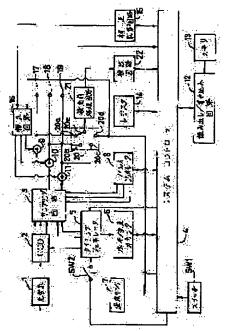
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### (54) DEFECT PICTURE ELEMENT DETECTION CIRCUIT FOR SOLID-STATE IMAGE PICKUP DEVICE

#### (57)Abstract:

PURPOSE: To detect a defect picture element and to prevent mis-detection of an output not being a detection object by erasing position data stored in a register when a picture element corresponding to position data stored in the register is not detected consecutively as a defect picture element for a prescribed number of times so as to exclude the effect depending on the condition at detection.

CONSTITUTION: The circuit is provided with a system controller 4 detecting a defect picture element outputting a signal of a specific level in each picture element of a CCD element 2 based on an output signal of the CCD element 2, a switch 20, a detection preprocessing circuit 21, a detection circuit 22 and a register 14 storing position data of a detected defect picture element. When a picture element corresponding to position data is not detected as a defect picture element consecutively for 10 times or over, the position data stored in the register 14 are erased.



#### **LEGAL STATUS**

[Date of request for examination]

16.03.1999

Date of sending the examiner's decision of

14.09.1999

rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]